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BIBDATASHEET

CONFIRMATION NO. 5086

Bib Data Sheet									
SERIAL NUMBER 10/715,264 FILING DATE 11/17/2003 RULE		CLASS 156		GROUP ART UNIT 1763		ATTORNEY DOCKET NO. 2269-4375.3US (99- 1029.03			
APPLICANTS				 ,					
Nathan R. Brown, Cedar Park, TX;									
** CONTINUING DATA **********************************									
Foreign Priority claimed yes no 35 USC 119 (a-d) conditions yes no Met after				STATE OR	SHEETS	тот	AL	INDEPENDENT	
met Verified and Acknowledged Examiner's Signature Initials				COUNTRY TX	DRAWING 7	CLAI 12		CLAIMS 2	
ADDRESS 24247 TRASK BRITT P.O. BOX 2550 SALT LAKE CITY, UT 84110									
TITLE Methods for determining amounts and locations of differential pressure to be applied to semiconductor substrates during polishing of semiconductor device structures carried thereby and for subsequently polishing similar semiconductor device structures									
				•		All Fees			
	FEES: Authority has been given in Paper No to charge/credit DEPOSIT ACCOUNT					1.16 Fees (Filing) 1.17 Fees (Processing Ext. of			
RECEIVED 770	No for following:			time)					